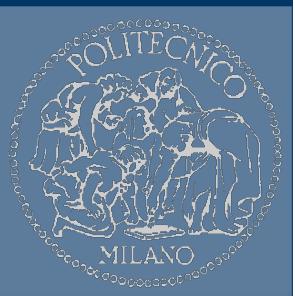


*Advanced course on*

## HIGH RESOLUTION ELECTRONIC MEASUREMENTS IN NANO-BIO SCIENCE

POLITECNICO DI MILANO



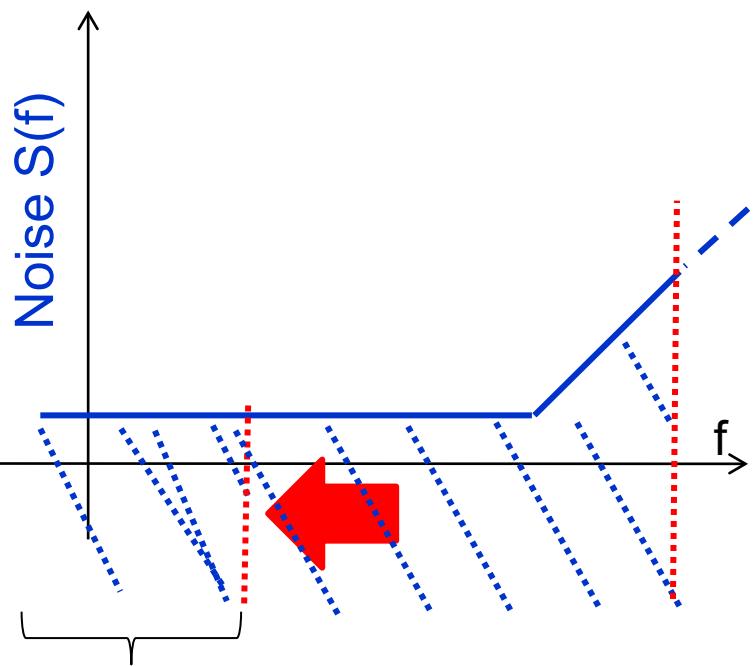
***Measurements  
at a given frequency***

**The Lock-in concept**

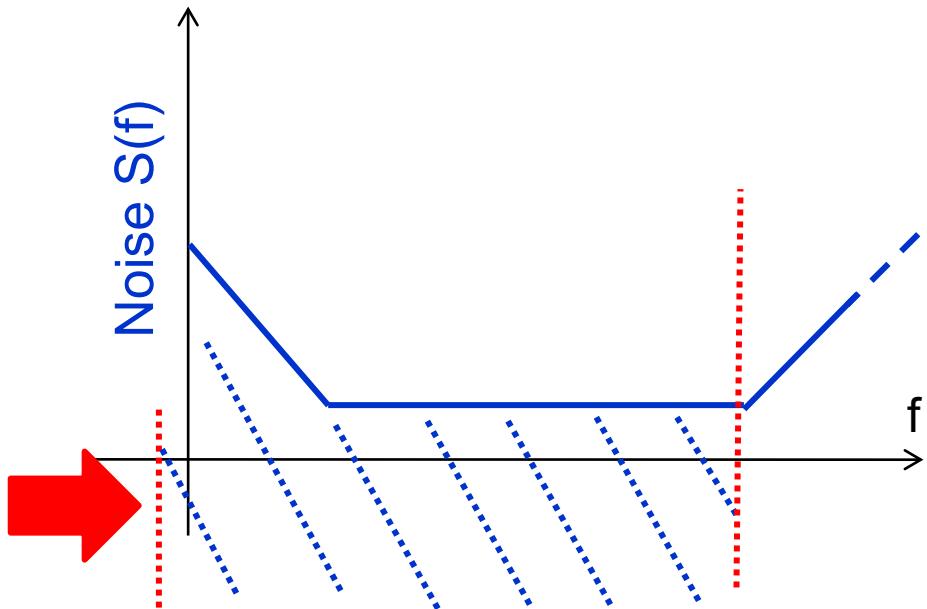


**Marco Sampietro**

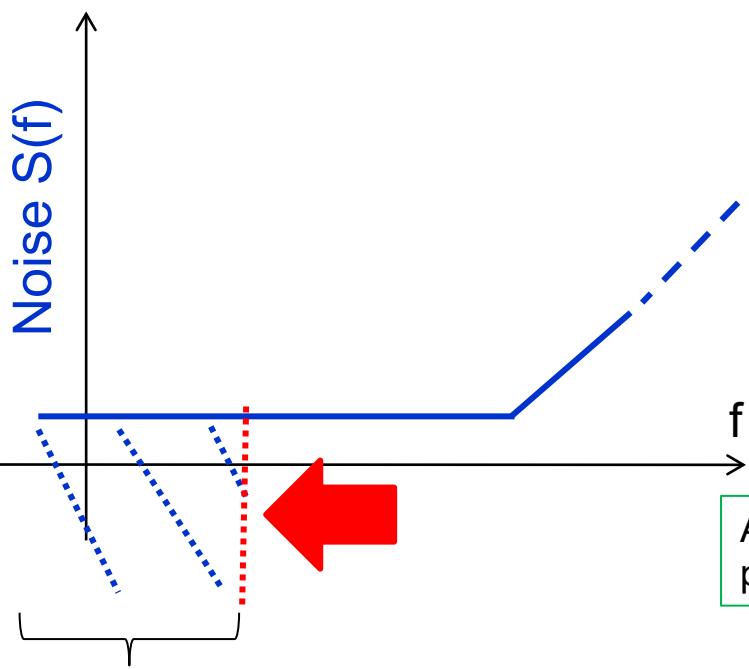
# Small bandwidth $\Rightarrow$ Low noise



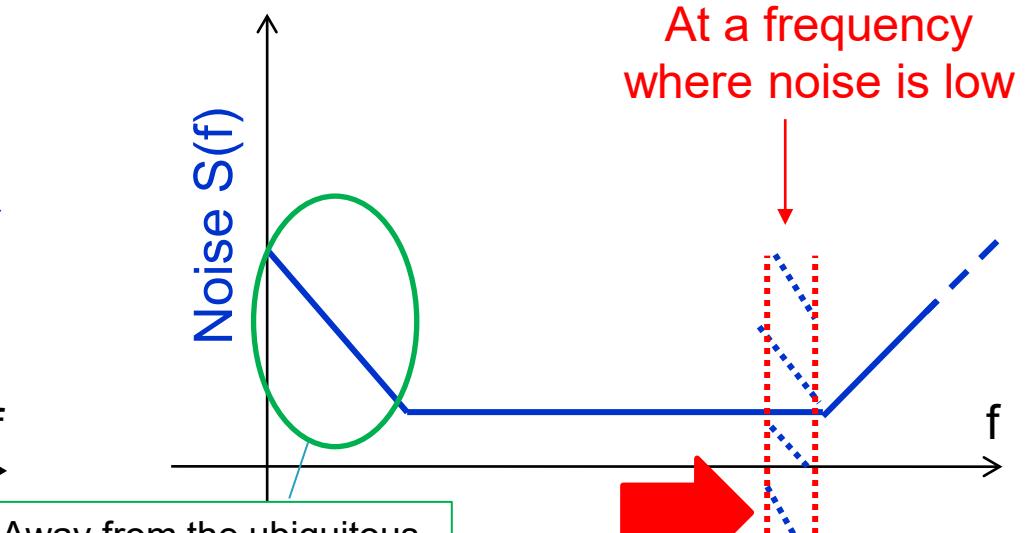
Small BW  $\rightarrow$  small noise



# ... small bandwidth at high frequency



Small BW  $\rightarrow$  small noise



Away from the ubiquitous presence of 1/f noise

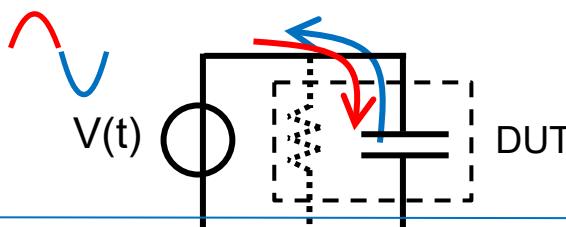
Small BW  $\rightarrow$  small noise

At a frequency where noise is low

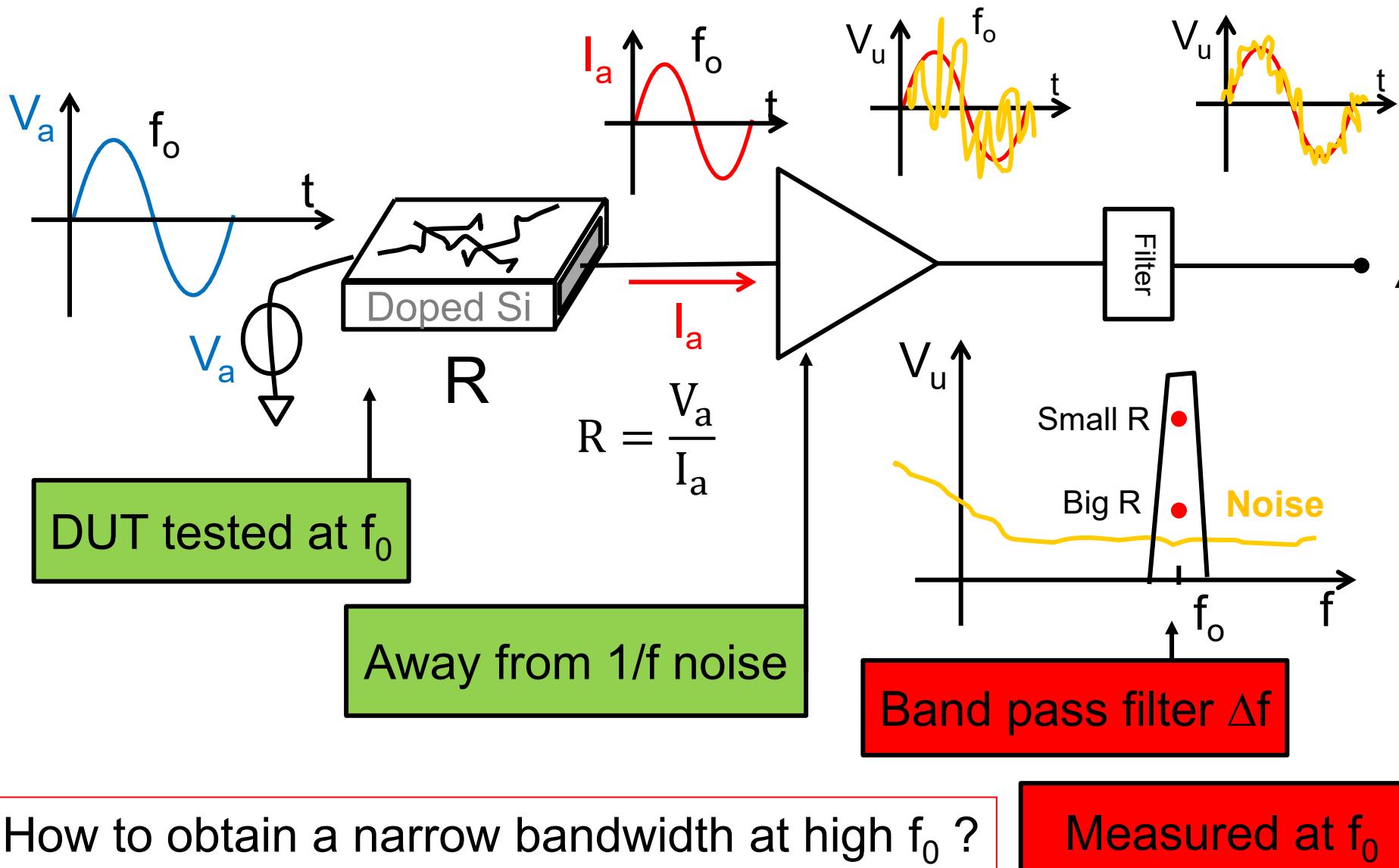
Signal is here

A repeated measurement at high frequency needs “**RECHARGEABLE**” events  
(AC electronic devices, reversible redox, pump&probe, ...)

Ex. : Induced charge on metal plates



# Example : measurement of R



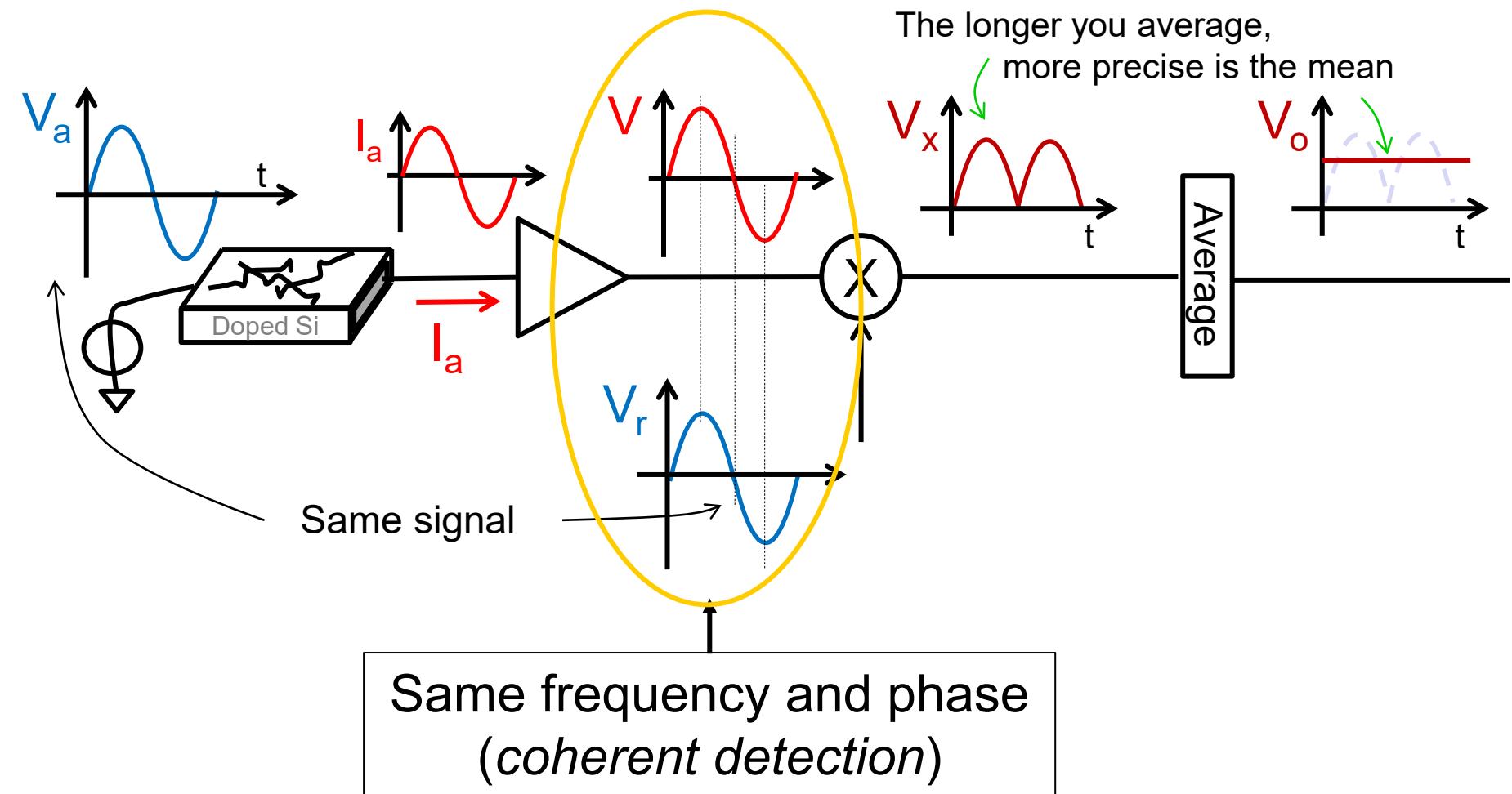


# Outline of the lesson

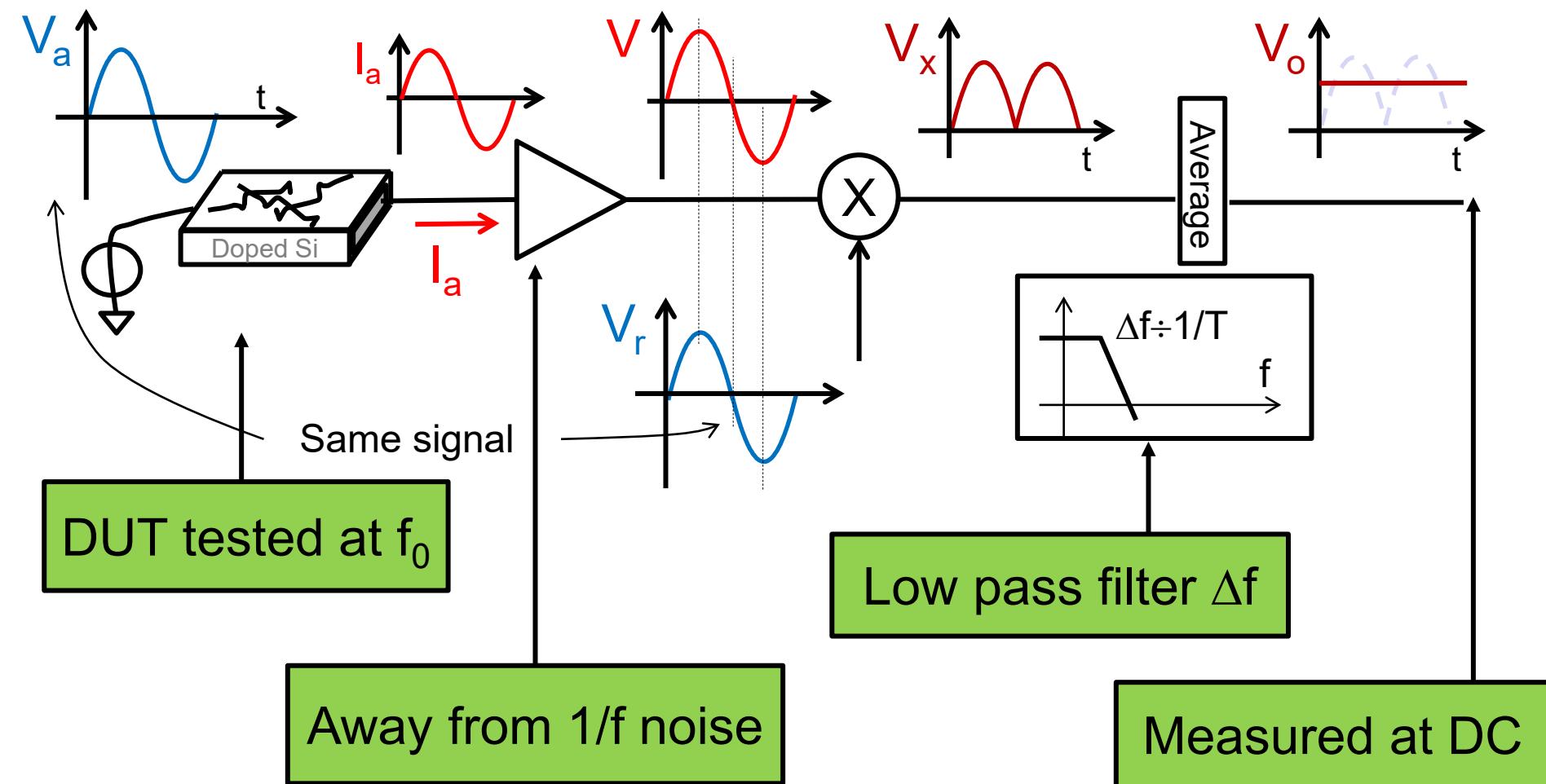


- The Lock-in concept 20 min
- Performance in sensitivity 20 min

# The LOCK-IN idea

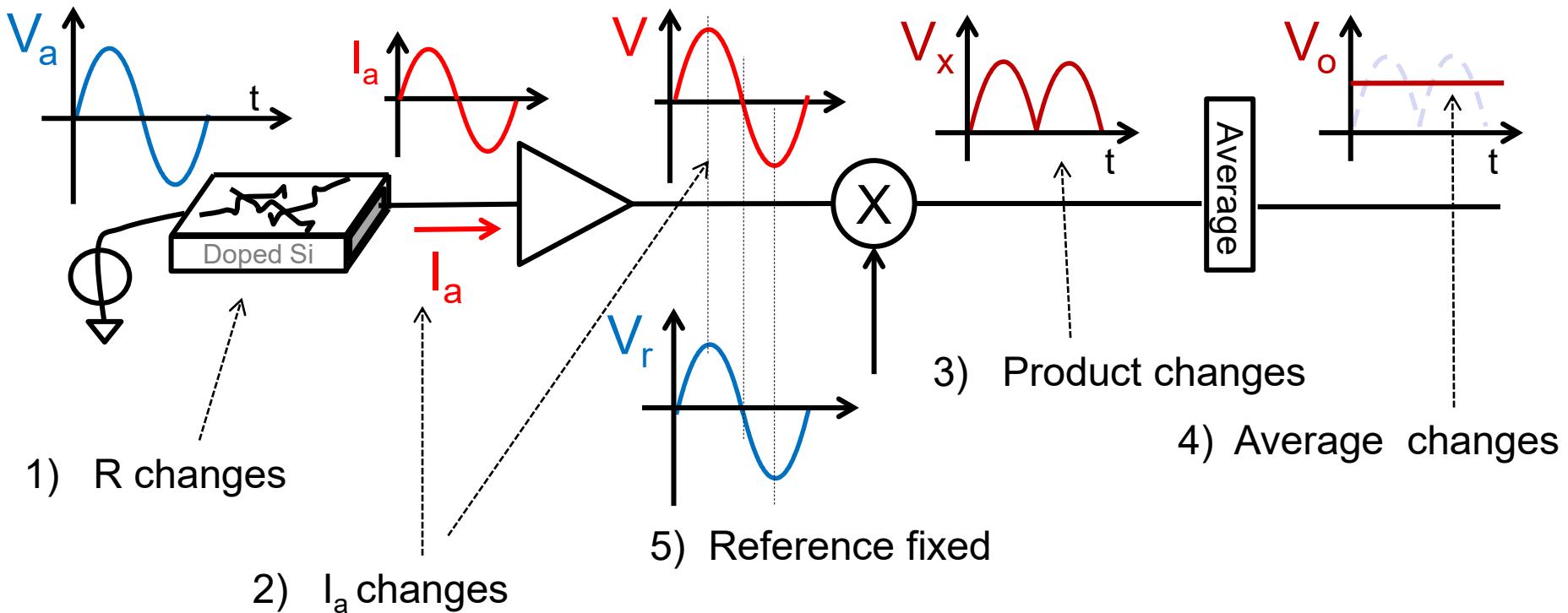


# The LOCK-IN idea



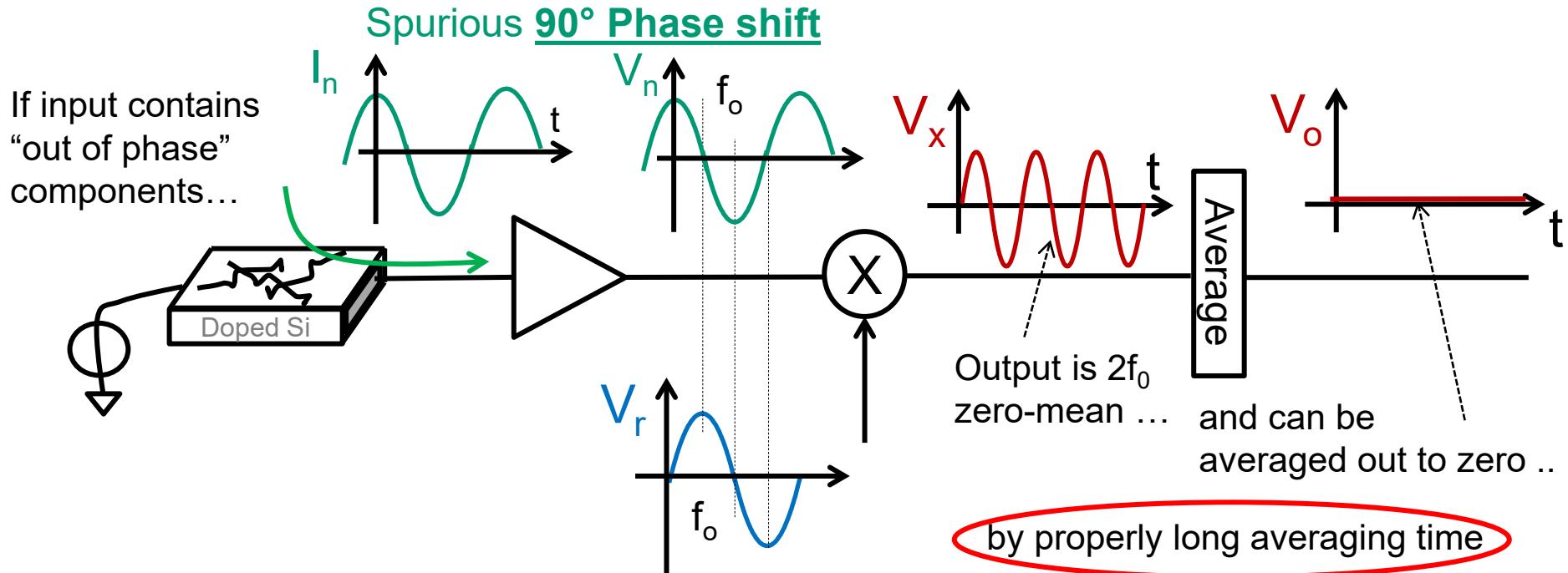
Credited to Robert Dicke, founder of Princeton Applied Research (PAR) in the 1960's.

# Tracking sensor with the LOCK-IN



DUT variations can be tracked with time by simply monitoring the level of the output

# Phase selectivity of the Lock-in



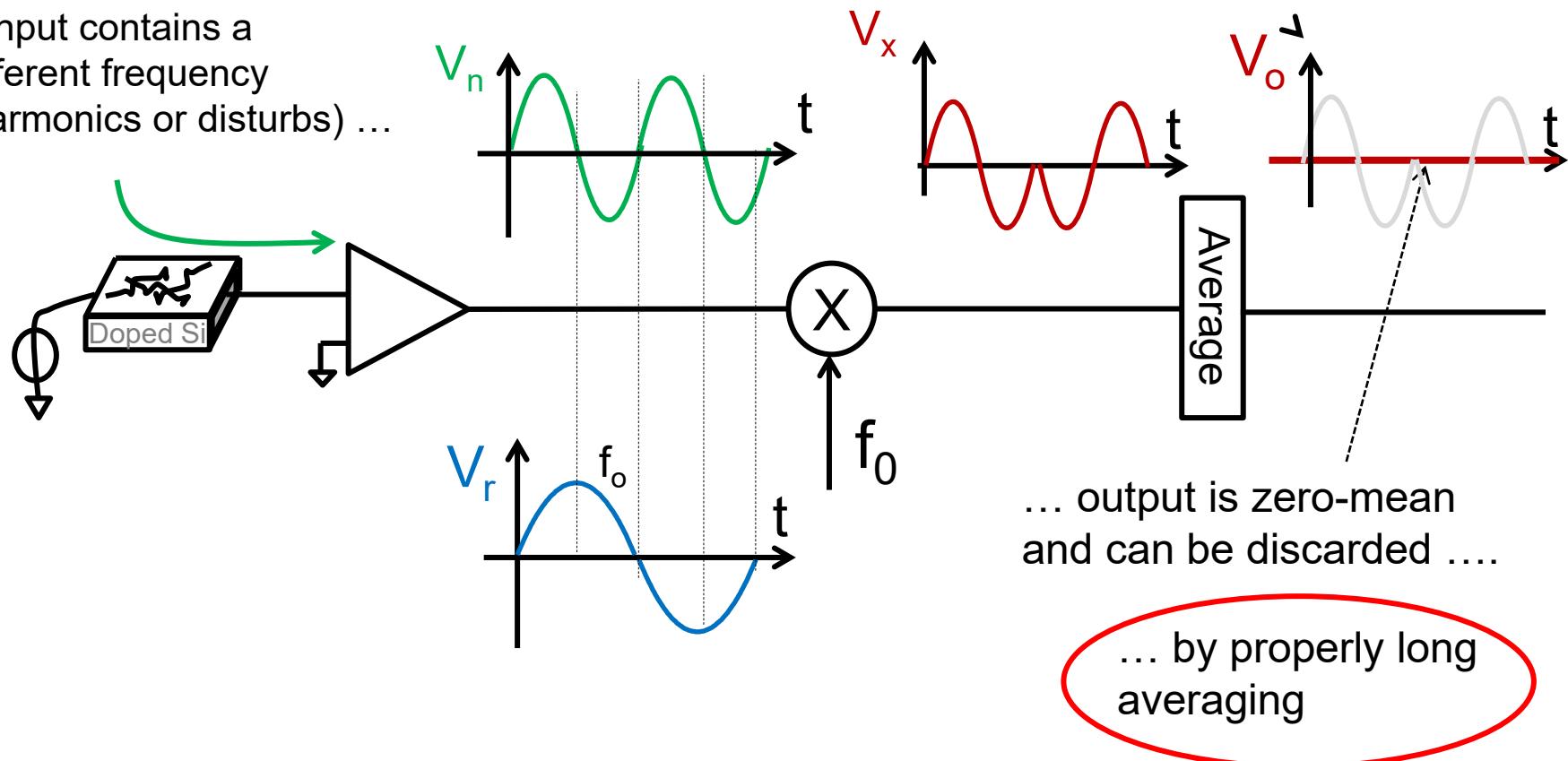
Small bandwidth  $\rightarrow$  Long averaging time  $\rightarrow$  High rejection of «spurious»

Long measurement time  $\downarrow$  Low noise

Signals with  $90^\circ$  **phase-shift** to reference are rejected

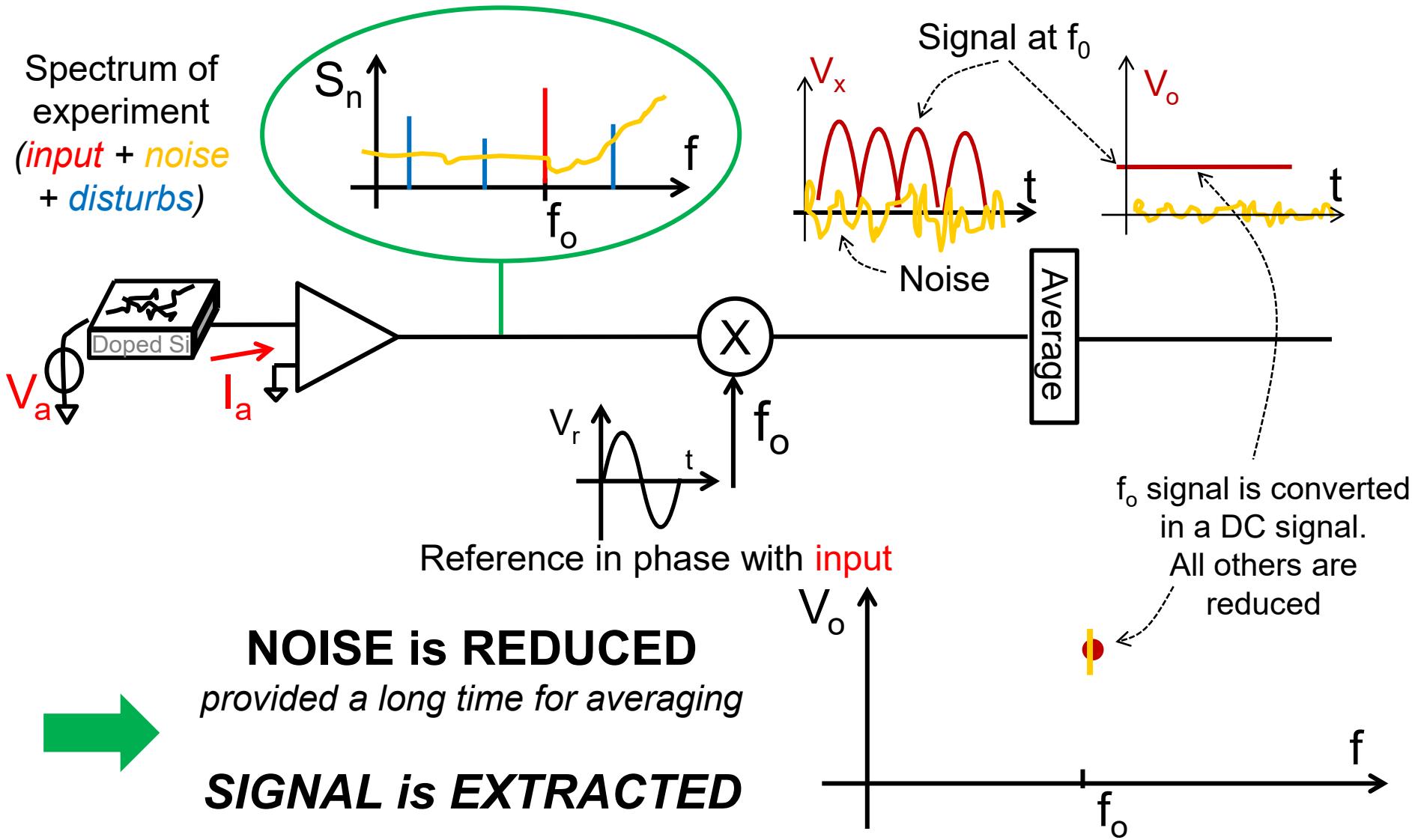
# Frequency selectivity of the Lock-in

If input contains a different frequency  
(harmonics or disturbs) ...



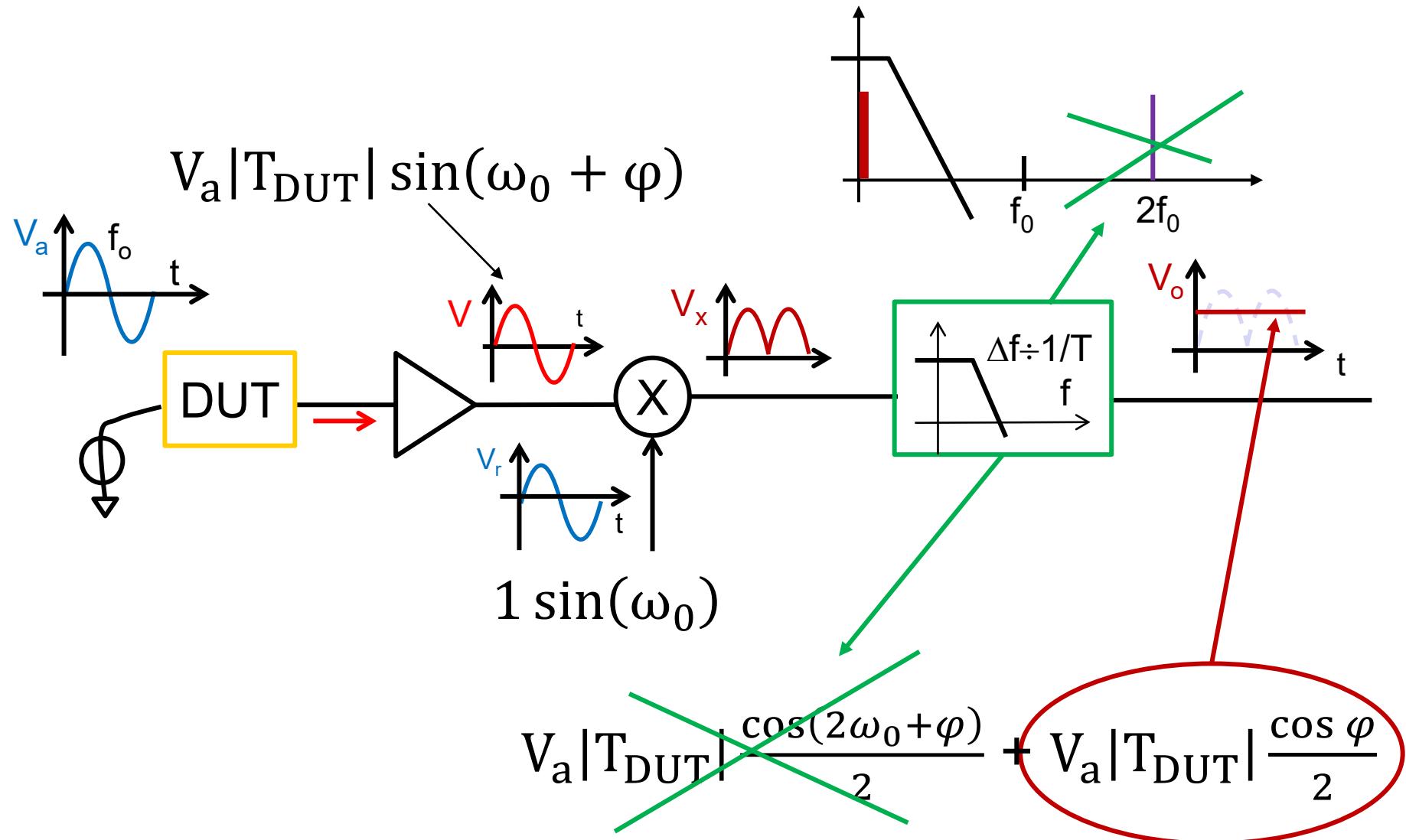
Signals with different frequency to reference are rejected

# Noise suppression





# Analytical view - Signal

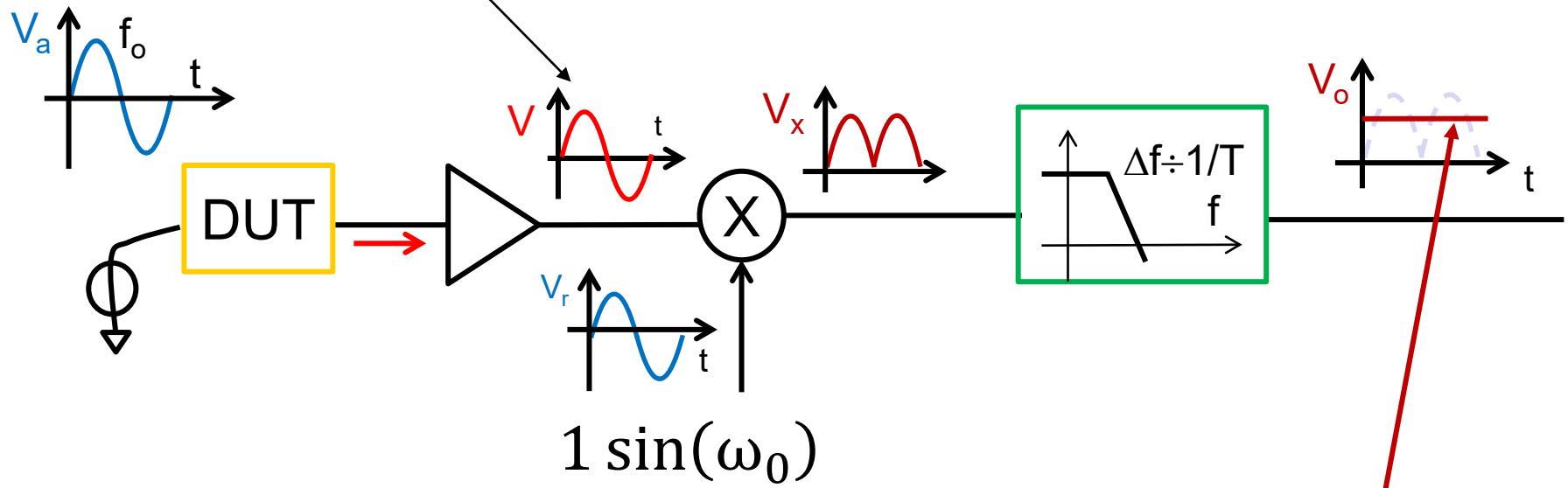


# Analytical view - Power

$$P_{in} = \frac{(V_a |T_{DUT}|)^2}{2}$$

$$P_{out} = \left( V_a |T_{DUT}| \frac{\cos \varphi}{2} \right)^2$$

$$V_a |T_{DUT}| \sin(\omega_0 + \varphi)$$

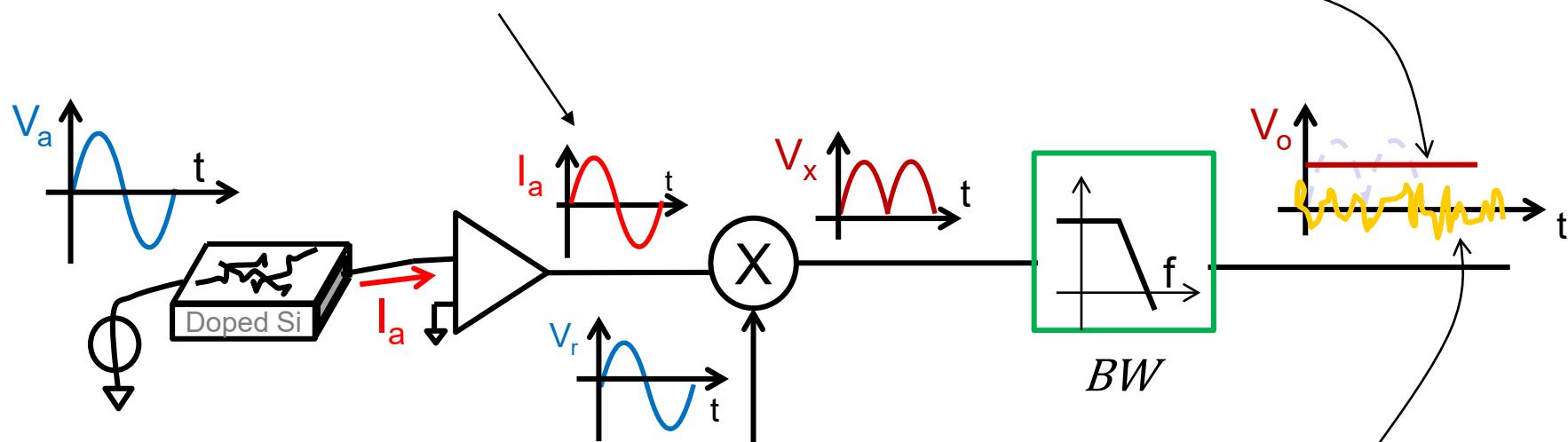


$$V_a |T_{DUT}| \frac{\cos \varphi}{2}$$

# Signal to Noise RATIO

$$P_{in|signal} = \frac{(V_a |T_{DUT}|)^2}{2}$$

$$P_{out|signal} = \left( V_a |T_{DUT}| \frac{\cos \varphi}{2} \right)^2$$



$$1 \sin(\omega_0)$$

$$P_{out|noise} = S_{in|noise}(f_0) \cdot \frac{1}{2} \cdot BW$$

$$\frac{P_{in|signal}}{P_{in|noise}} = \frac{P_{in|signal} \cdot \frac{1}{2}}{S_{in|noise}(f_0) \cdot \frac{1}{2} \cdot BW} = \frac{P_{out|signal}}{P_{out|noise}}$$

*(Note: The term  $\frac{1}{2}$  is crossed out with a red line.)*

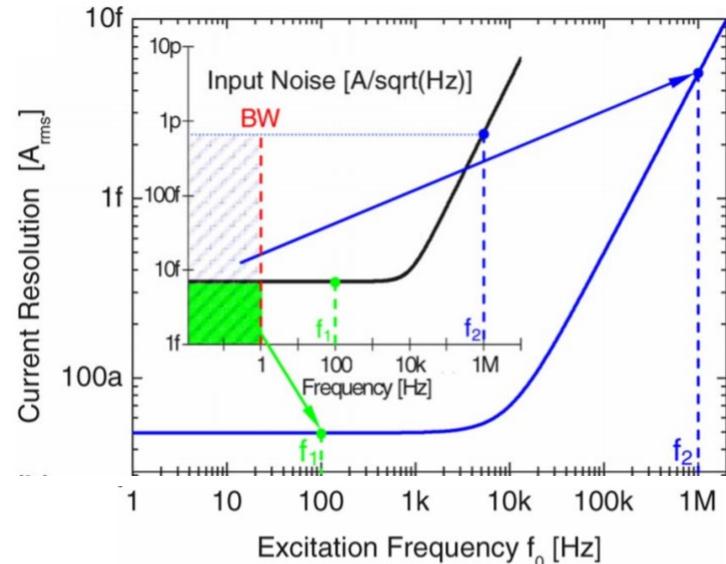
*same BW of the lock-in around  $f_0$*

The Lock-in can be considered an optimal detector of AC signals

# Lock-In Noise Filtering

$$\frac{P_{in|signal}}{P_{in|noise}} = \frac{P_{in|signal}}{S_{in|noise}(f_0) \cdot BW}$$

- The modulation *whiten* the noise spectrum in base band at the value sampled at  $f_0$
- The order of the filter is not critical for the noise (a first order is ok even with non-white noise)
- The filter has to properly cut the  $2f_0$  component



M. Carminati et al. "Attofarad resolution potentiostat for electrochemical measurements on nanoscale biomolecular interfacial systems," Rev. Sci. Instrum., vol. 80, no. 12, p. 124701 (2009), doi: 10.1063/1.3245343.

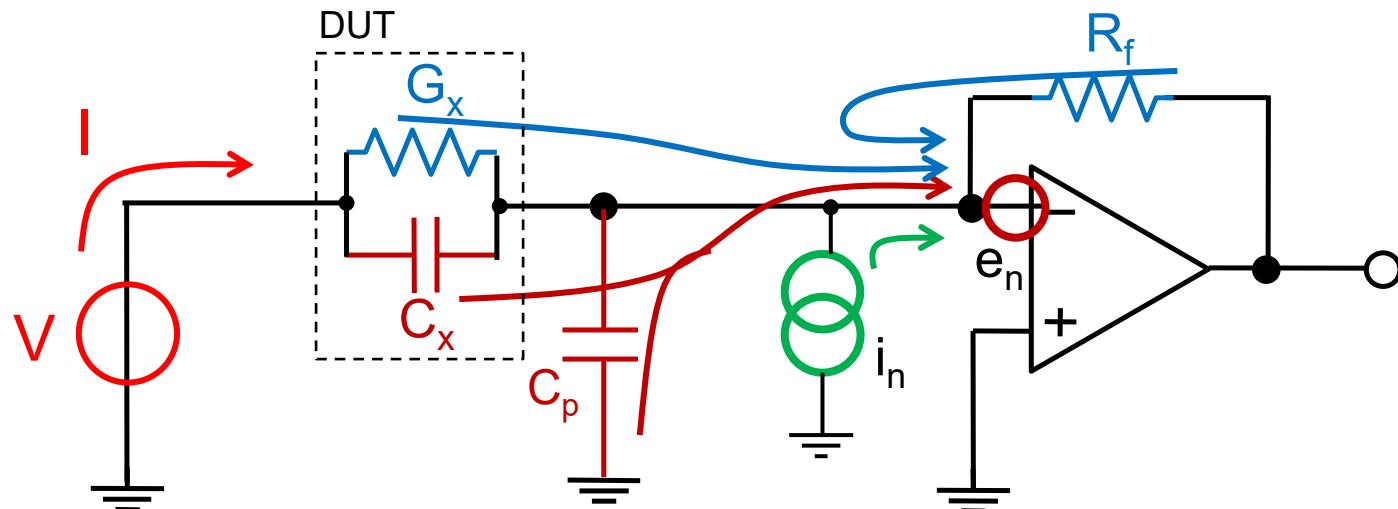


# Outline of the lesson

- The Lock-in concept 20 min
- Performance in sensitivity 20 min

# Limit of sensitivity : Noise Analysis

A recap of the input noise of the TIA :

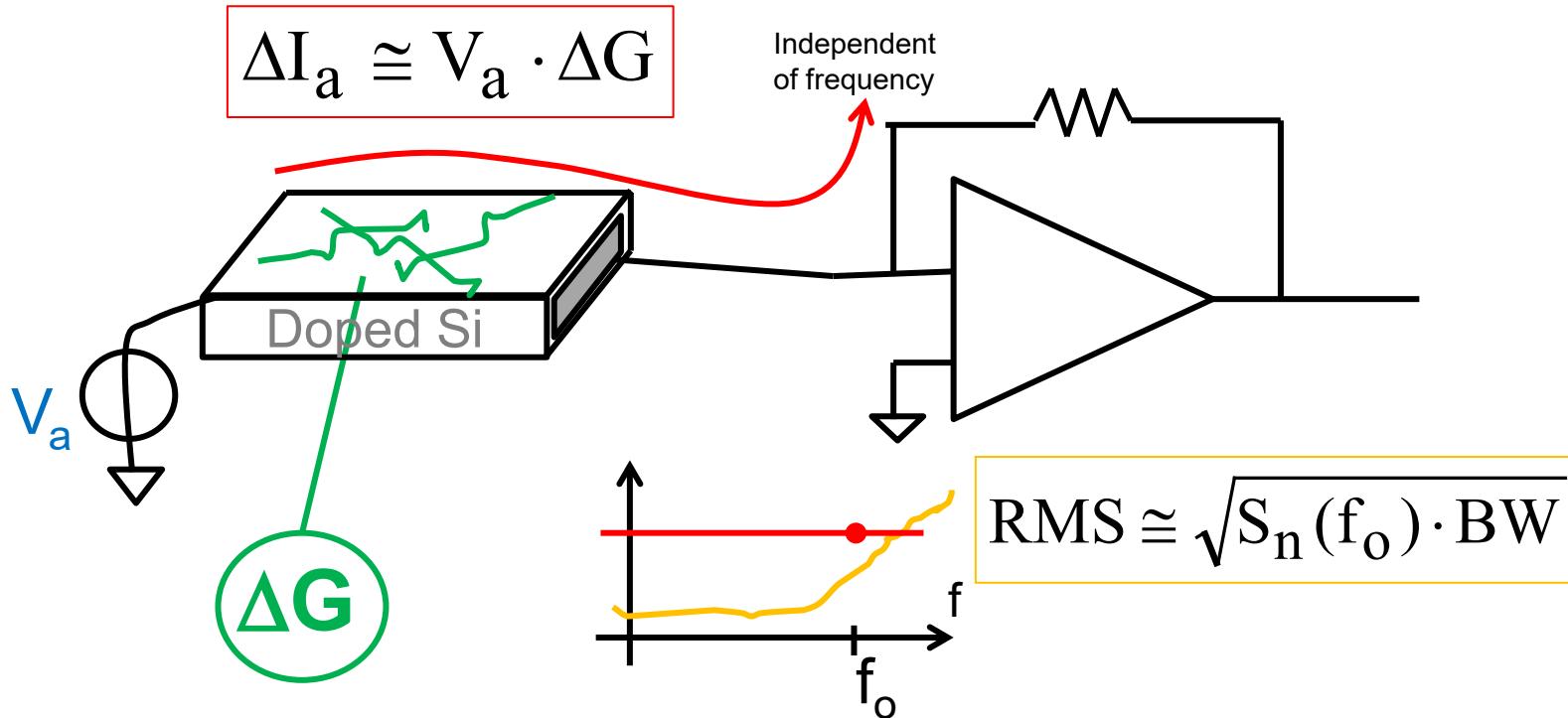


$$S_i = \bar{i_n^2} + 4kT(G_x + G_f) + \bar{e_n^2}\omega^2(C_x + C_p)^2 + \bar{e_n^2}(G_x + G_f)^2$$

To be compared with the Signal ( $V$ ,  $I$ )



# Limit of sensitivity - for R

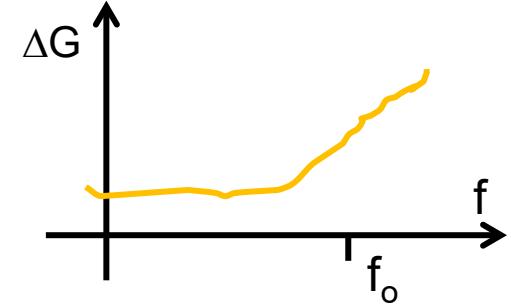


The limit of detection is reached when

$$\Delta I_a \approx RMS$$



$$\Delta G \approx \frac{\sqrt{S_n(f) \cdot BW}}{V_a}$$



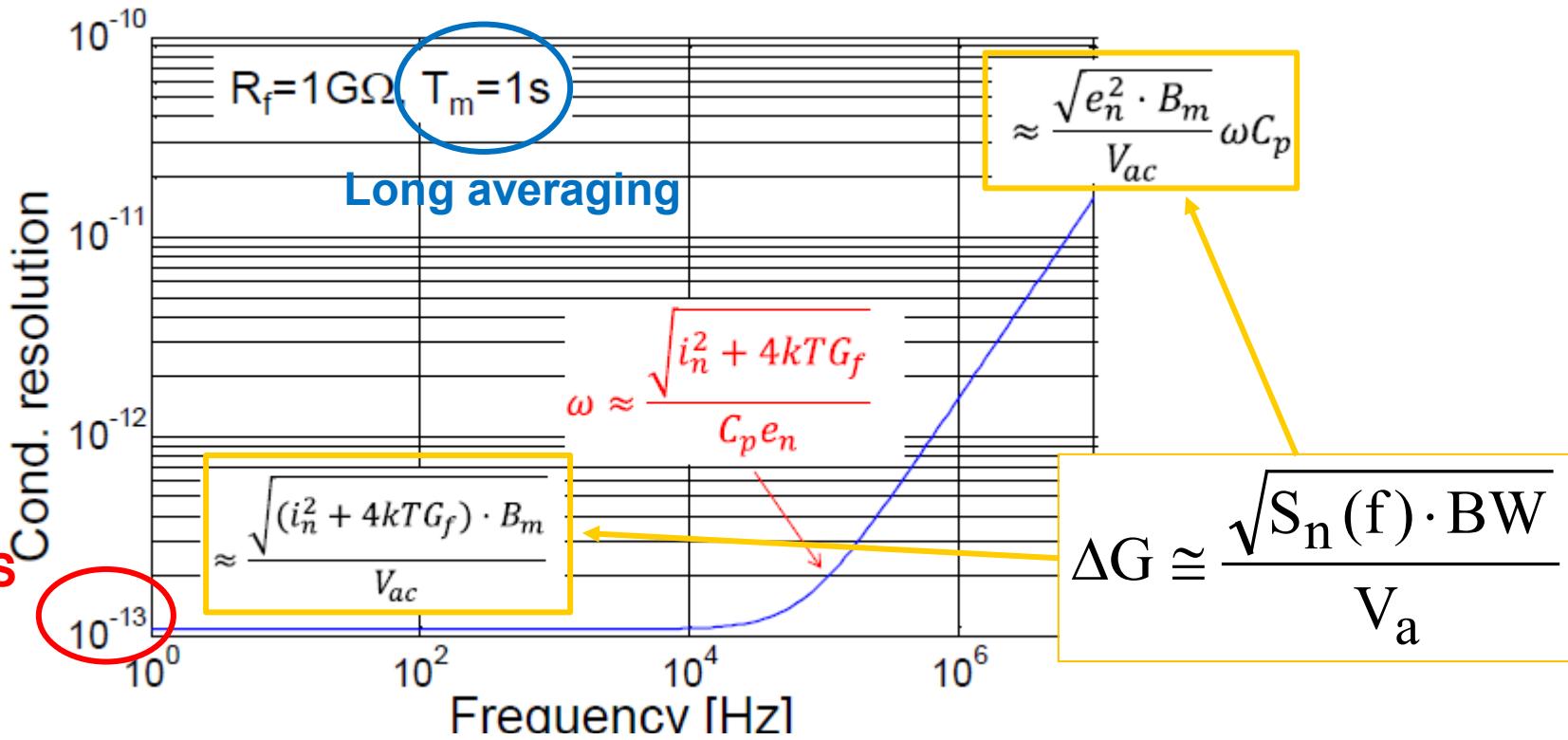
# Limit of sensitivity - for R

Still margin of improvement !

$$e_n = \frac{5nV}{\sqrt{\text{Hz}}}, i_n = \frac{10fA}{\sqrt{\text{Hz}}}, V_{ac} = 100mV, C_p = 5pF, C_x \ll C_p$$

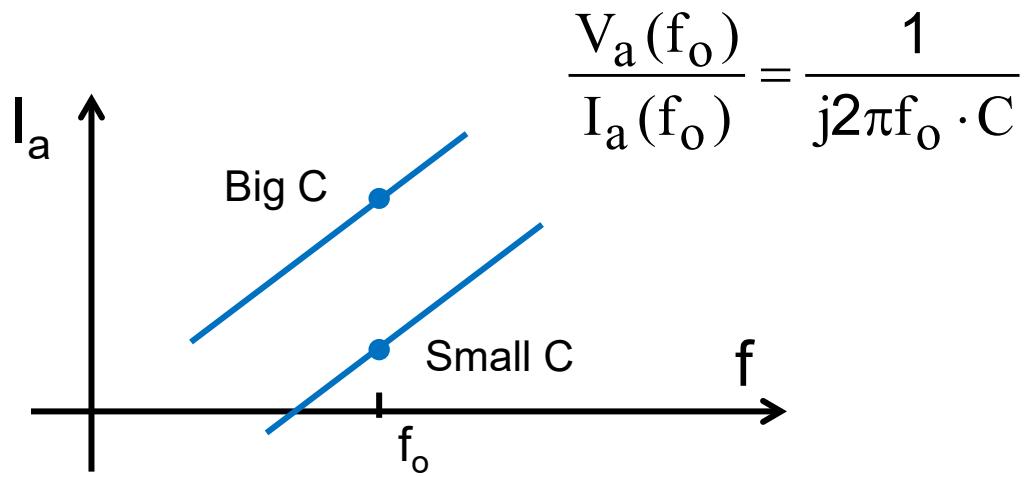
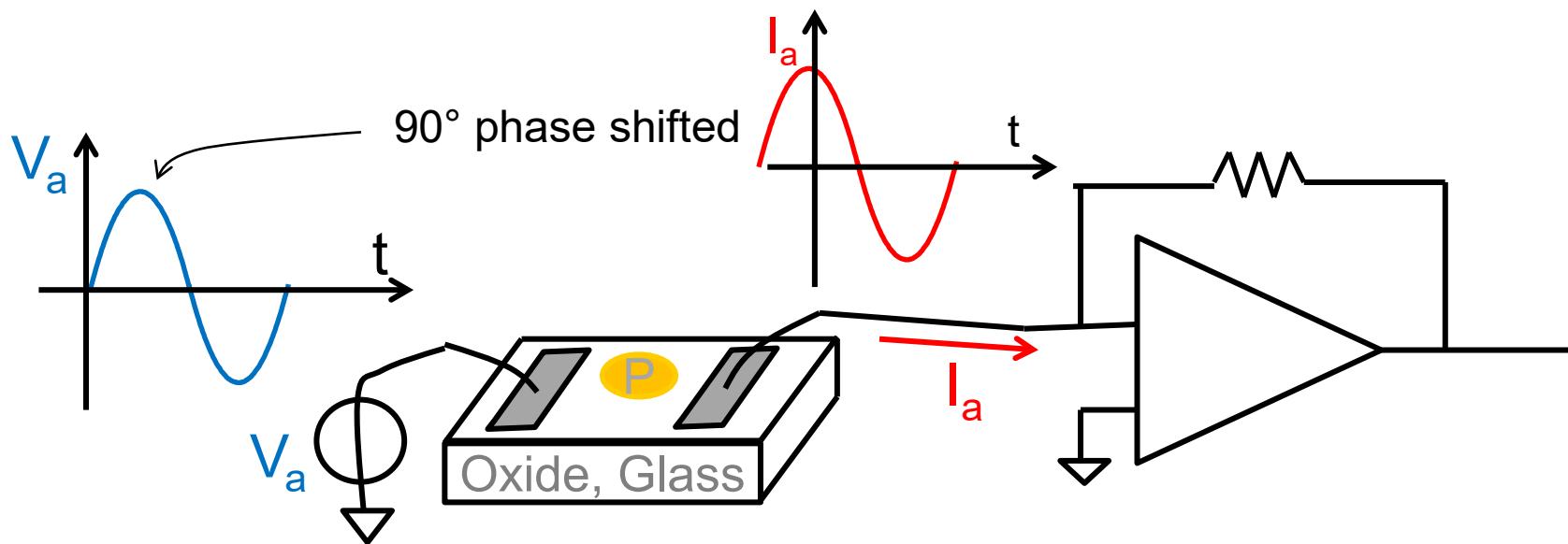
Good electronics

Good mounting

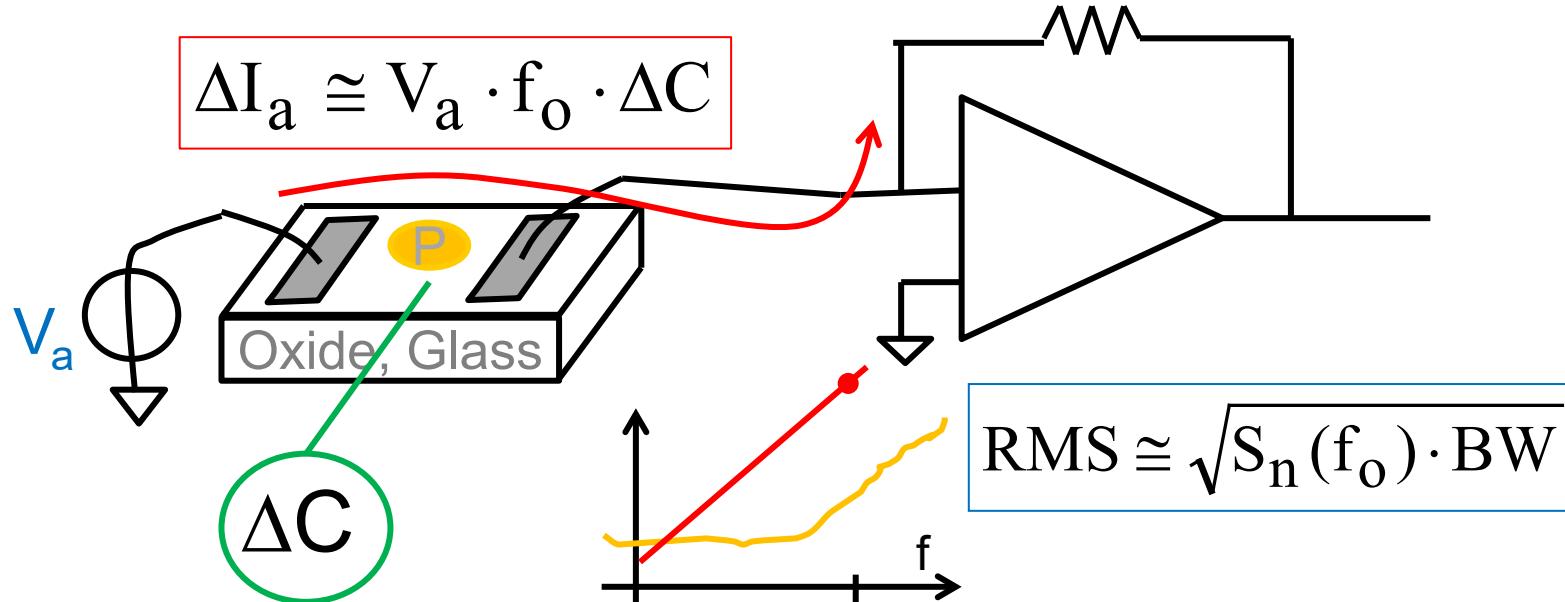


$$S_i = \overline{i_n^2} + 4kT(G_x + G_f) + \overline{e_n^2}\omega^2(C_x + C_p)^2 + \overline{e_n^2}(G_x + G_f)^2$$

# Sinusoidal measurement of C



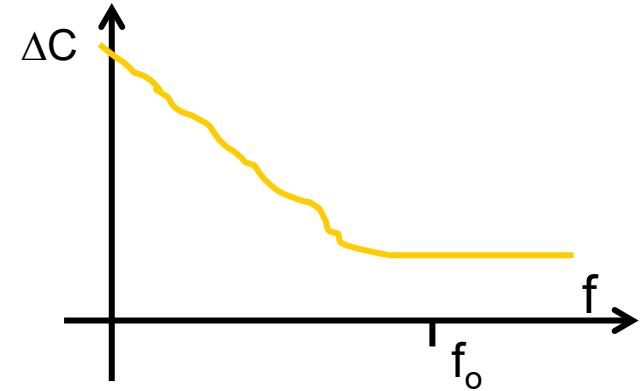
# Limit of sensitivity - for C



Limit when

$$\Delta I_a \approx RMS$$

$$\Delta C \approx \frac{\sqrt{S_n(f) \cdot BW}}{V_a \cdot f}$$



# Limit of sensitivity - for C

Still margin of improvement (see next slide) !

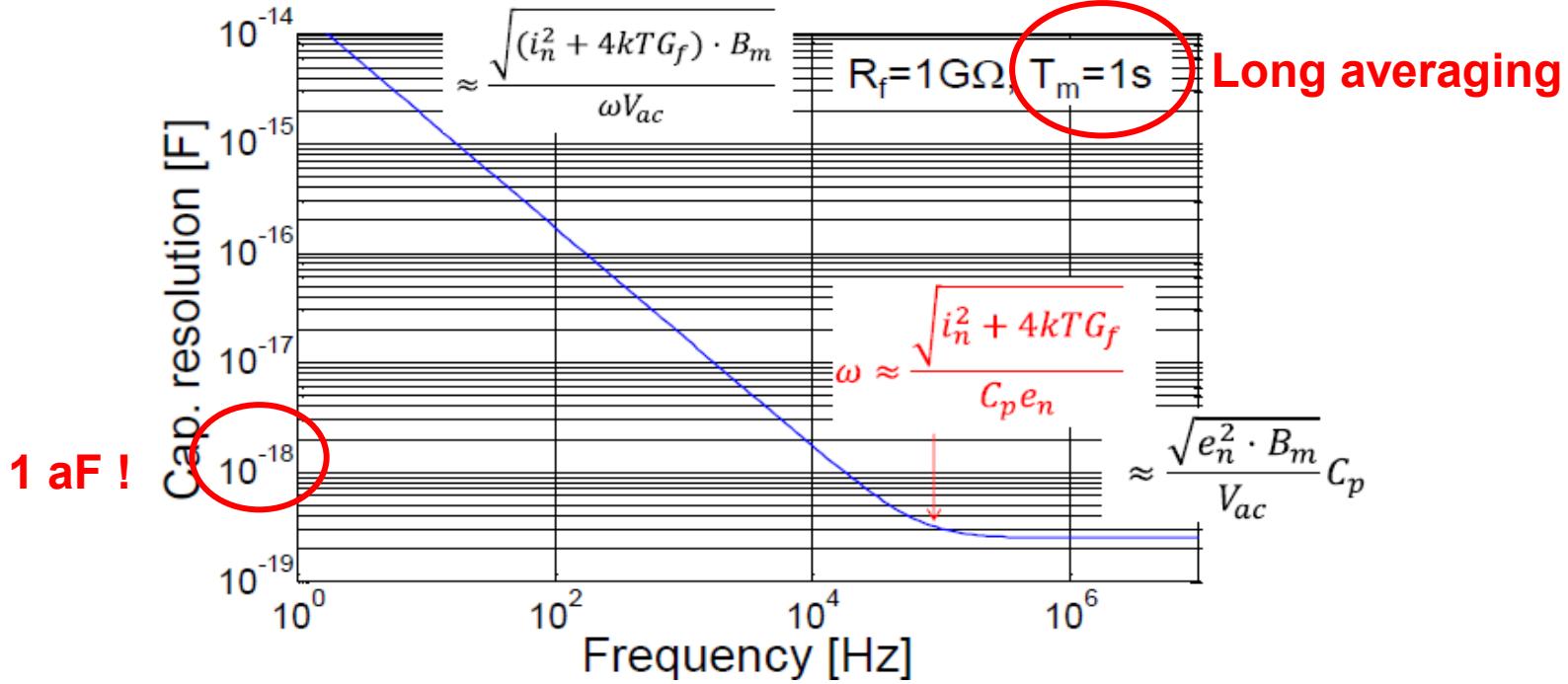
$$e_n = \frac{5nV}{\sqrt{\text{Hz}}}, i_n = \frac{10fA}{\sqrt{\text{Hz}}}$$

Good electronics

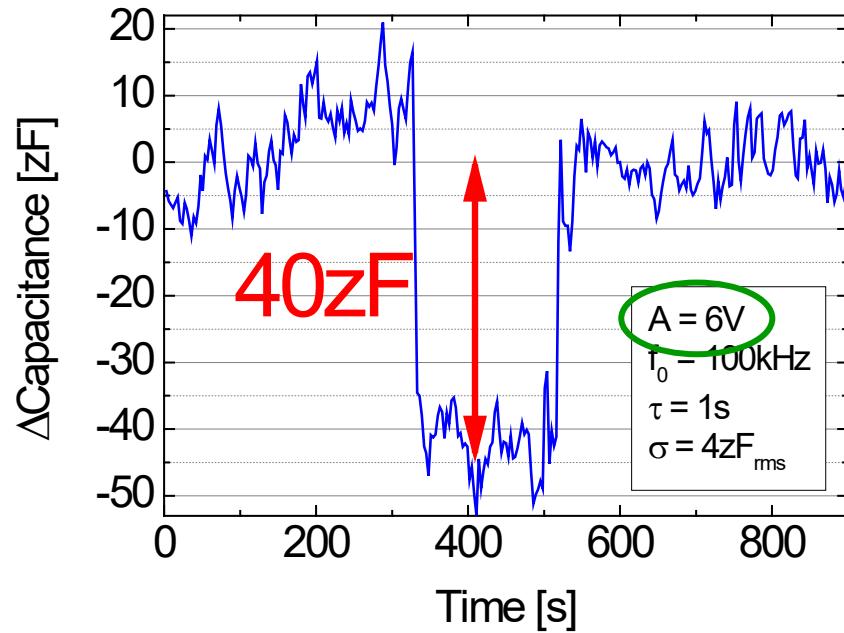
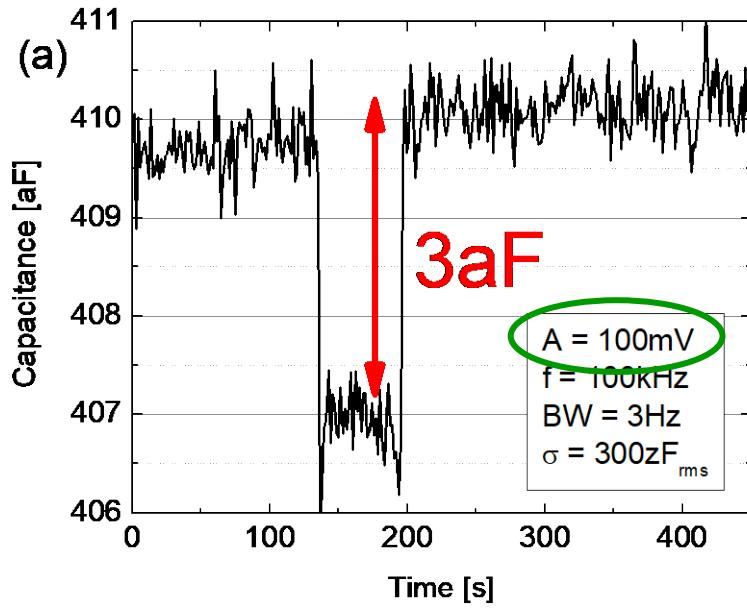
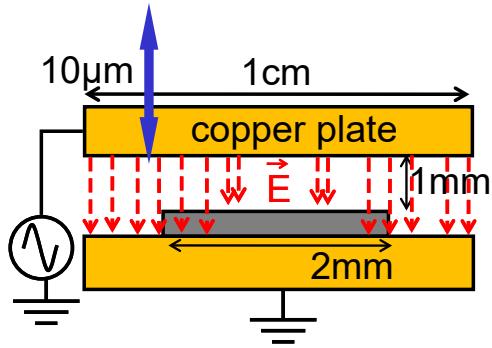
$$V_{ac} = 100mV$$

$$C_p = 5pF, C_x \ll C_p$$

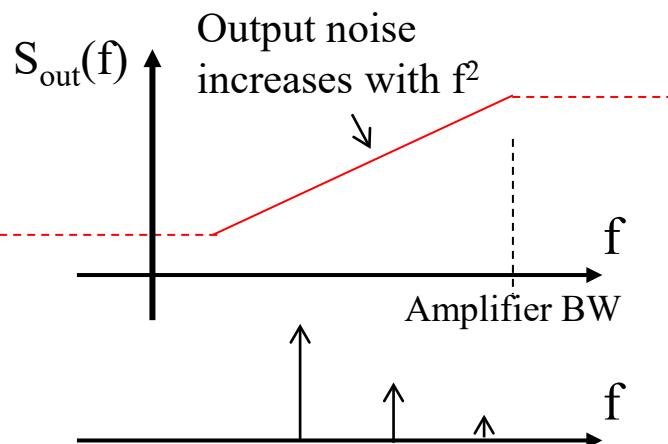
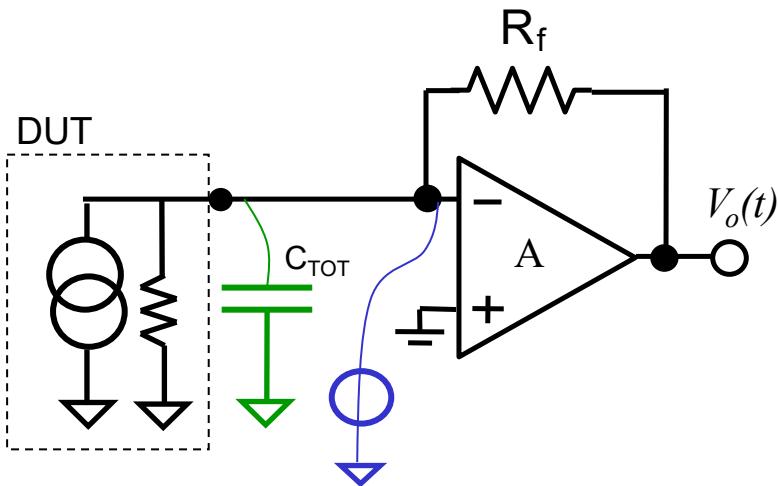
Good mounting



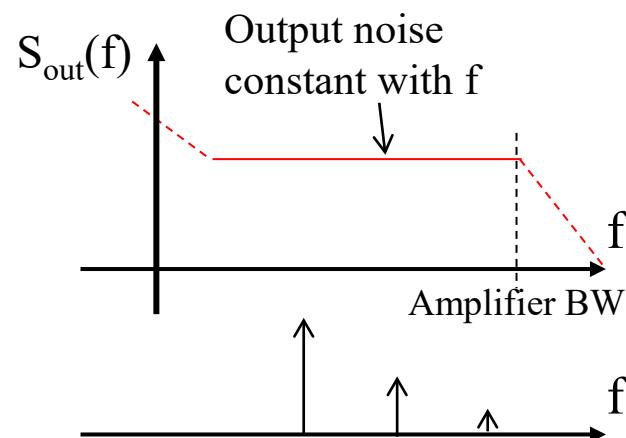
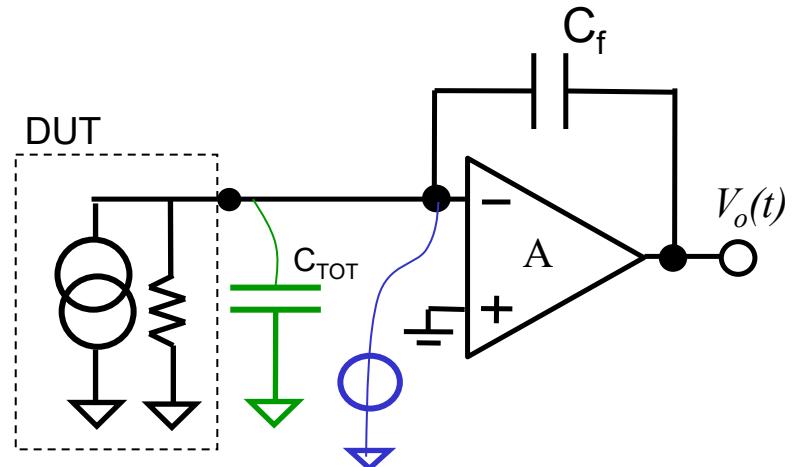
# Improvement with Voltage amplitude



# Special TIA for square wave mixer



If a square wave mixer is used, it introduces harmonics that fold a lot of noise



If a square wave mixer is used, higher harmonics give little noise



# In conclusion ...

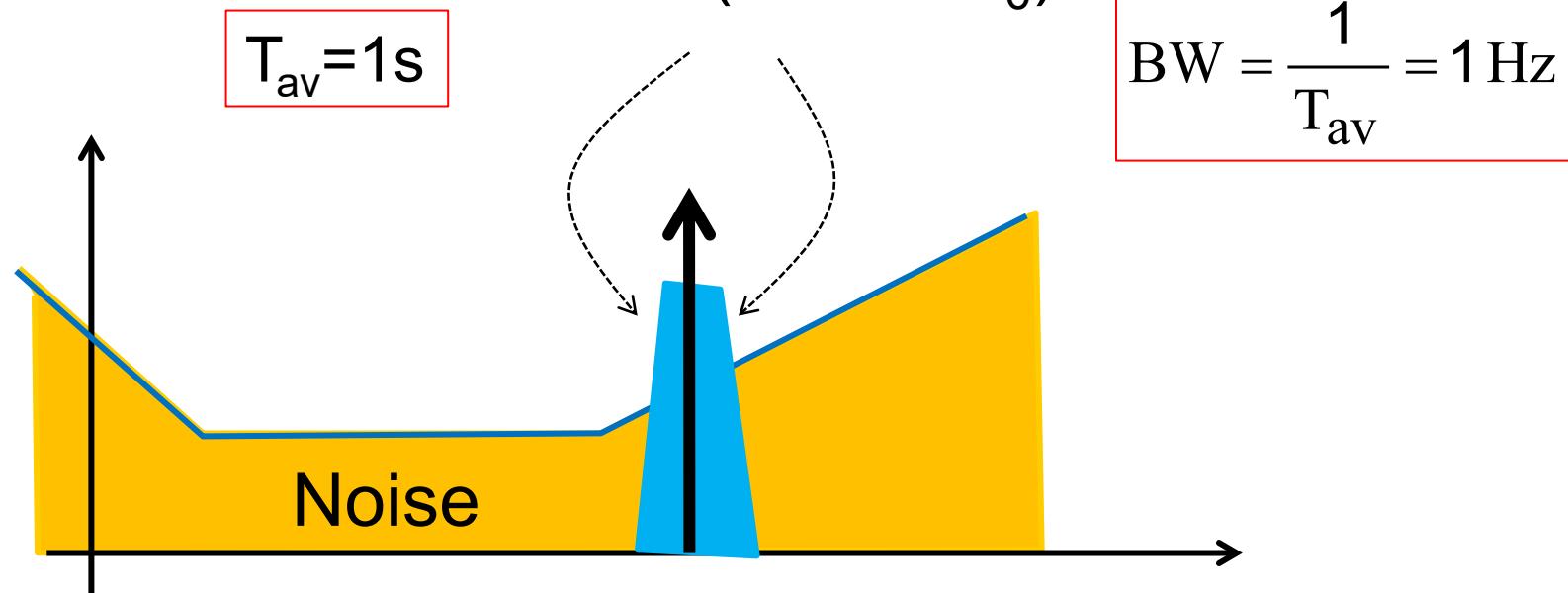
# Things to remember (1)

A Lock-in amplifier is «like» a band-pass filter at  $f_0$

Longer averaging

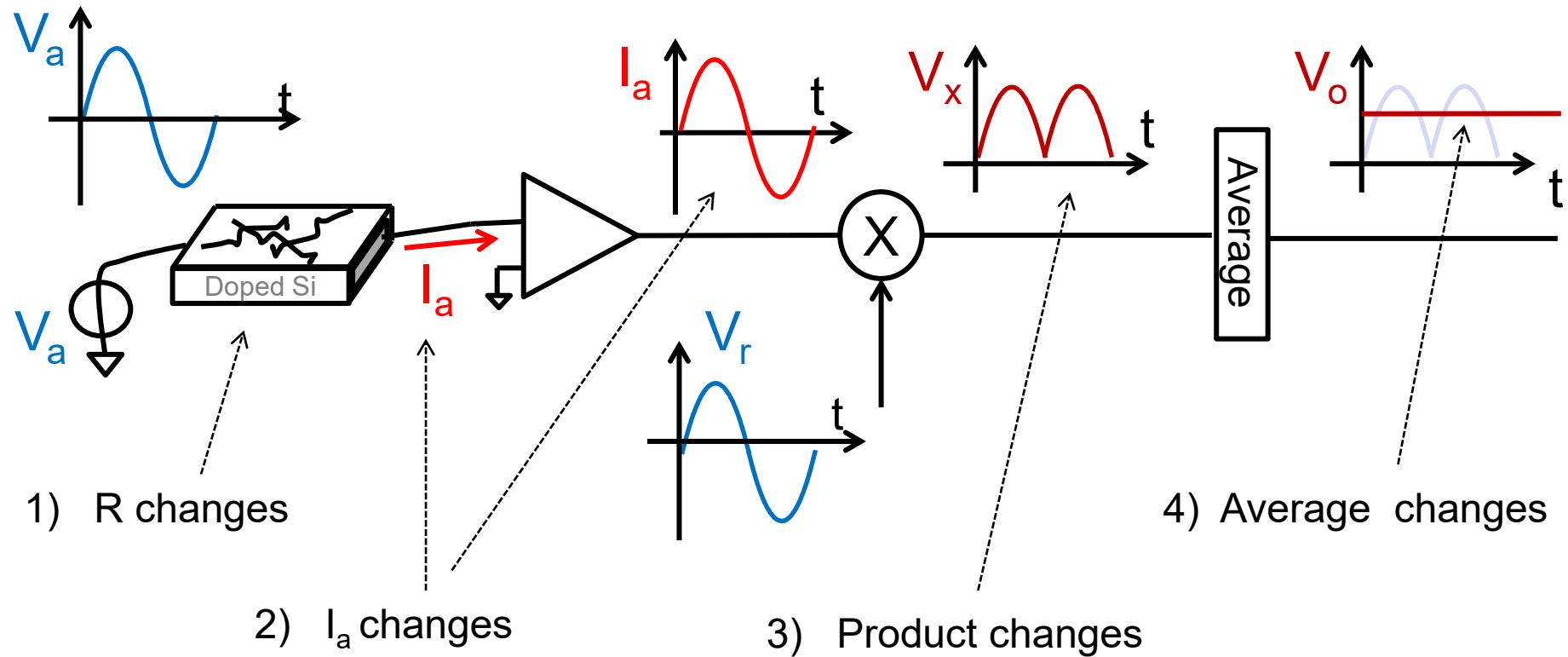


Thinner bandwidth  
(around  $f_0$ )



By changing measurement frequency  $f_0$ , you can choose the optimal position

# Things to remember (2)



Signal variations can be tracked with time by simply monitoring the level of the output

# Things to remember (3)

Extremely high sensitivity can be reached in device characterisation

